# **Power MOSFET**

# 40 V, 2.1 m $\Omega$ , 163 A, Single N–Channel

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

# **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	40	V
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain Cur-	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	163	Α
rent R <sub>θJC</sub> (Notes 1 & 3)		T <sub>C</sub> = 100°C		115	
Power Dissipation R <sub>θJC</sub>		T <sub>C</sub> = 25°C	P <sub>D</sub>	117	W
(Note 1)		T <sub>C</sub> = 100°C		58	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	26	Α
Current R <sub>0JA</sub> (Notes 1, 2 & 3)		T <sub>A</sub> = 100°C		22	
Power Dissipation R <sub>θJA</sub>		T <sub>A</sub> = 25°C	P <sub>D</sub>	3.2	W
(Notes 1 & 2)		T <sub>A</sub> = 100°C		2.2	
Pulsed Drain Current	Drain Current $T_A = 25^{\circ}C$ , $t_p = 10 \mu s$			900	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to 175	°C
Source Current (Body Diode)			IS	130	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, I <sub>L(pk)</sub> = 25 A)			E <sub>AS</sub>	420	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Note 1)	$R_{\theta JC}$	1.28	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	48	

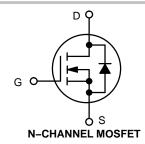
- 1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface–mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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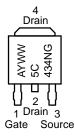
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
40 V	2.1 mΩ @ 10 V	163 A





DPAK CASE 369C STYLE 2

#### MARKING DIAGRAM & PIN ASSIGNMENT



A = Assembly Location

Y = Year
WW = Work Week
5C434N= Device Code
G = Pb-Free Package

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Temperature Coefficient   Total Care   To	Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
Drain-to-Source Breakdown Voltage   Temperature Coefficient   Temp	OFF CHARACTERISTICS							
Temperature Coefficient   Total Care   To	Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Section		V <sub>(BR)DSS</sub> /T <sub>J</sub>				18		mV/°C
State	Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$			10	μΑ
ON CHARACTERISTICS (Note 4)         VGS(TH)         VGS = VDS, ID = 250 μA         2.0         4.0         V           Regative Threshold Temperature Coefficient VGS(TH)/TJ         VGS = 10 V, ID = 50 A         1.7         2.1         mV/D           Drain-to-Source On Resistance         RDS(on)         VGS = 10 V, ID = 50 A         1.7         2.1         mK           Forward Transconductance         grs         VDS = 3 V, ID = 50 A         1.55         S           CHARGES, CAPACITANCES AND GATE RESISTANCES           Input Capacitance         Ciss         VGS = 0 V, f = 1.0 MHz, VGS = 25 V         3000         PF           Output Capacitance         Crss         VGS = 0 V, f = 1.0 MHz, VGS = 25 V         3000         PF           Total Gate Charge         QG(TOT)         ARCHIVAL AND			$V_{DS} = 40 \text{ V}$	T <sub>J</sub> = 125°C			250	1
Gate Threshold Voltage         V <sub>GS</sub> (TH)         V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA         2.0         4.0         V           Negative Threshold Temperature Coefficient         V <sub>GS</sub> (TH)/T <sub>J</sub> 7.9         mV/D           Drain-to-Source On Resistance         R <sub>DS</sub> (on)         V <sub>GS</sub> = 10 V, I <sub>D</sub> = 50 A         1.7         2.1         ms           Forward Transconductance         g <sub>FS</sub> V <sub>DS</sub> = 3 V, I <sub>D</sub> = 50 A         1.55         S           CHARGES, CAPACITANCES AND GATE RESISTANCES           Input Capacitance         C <sub>Iss</sub> V <sub>DS</sub> = 3 V, I <sub>D</sub> = 1.0 MHz, V <sub>DS</sub> = 32 V, I <sub>D</sub> = 50 A         3000         P           Output Capacitance         C <sub>Iss</sub> V <sub>GS</sub> = 0 V, I = 1.0 MHz, V <sub>DS</sub> = 25 V         3000         P           Everse Transfer Capacitance         C <sub>Iss</sub> V <sub>GS</sub> = 0 V, I = 1.0 MHz, V <sub>DS</sub> = 25 V         3000         P           Total Gate Charge         Q <sub>G</sub> (TOT)         M <sub>S</sub> = 10 V, V <sub>DS</sub> = 32 V, I <sub>D</sub> = 50 A         80.6         P           Gate-to-Drain Charge         Q <sub>GS</sub> V <sub>GS</sub> 15.4         P           Gate-to-Drain Charge         V <sub>GP</sub> V <sub>GP</sub> V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 32 V, I <sub>D</sub> = 50 A         T         T           Turn-On Delay Time         t <sub>I</sub> V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 32 V, I <sub>D</sub> = 50 A, R <sub>G</sub> = 2.5 Ω         A3         <	Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	s = 20 V			100	nA
Negative Threshold Temperature Coefficient   V <sub>GS(TH)</sub> /T <sub>J</sub>   7.9   mV/Drain-to-Source On Resistance   R <sub>DS(on)</sub>   V <sub>GS</sub> = 10 V, I <sub>D</sub> = 50 A   1.7   2.1   mS/Drain-to-Source On Resistance   g <sub>FS</sub>   V <sub>DS</sub> = 3 V, I <sub>D</sub> = 50 A   1.55   S   S	ON CHARACTERISTICS (Note 4)							
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	2.0		4.0	V
Forward Transconductance   gFS	Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.9		mV/°C
	Drain-to-Source On Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_D$	= 50 A		1.7	2.1	mΩ
$ \begin{array}{ c c c c c } \hline & \text{Input Capacitance} & & & & & & & & & & & & & & & & & & &$	Forward Transconductance	9FS	$V_{DS} = 3 \text{ V}, I_{D}$	= 50 A		155		S
Output Capacitance         Coss Reverse Transfer Capacitance         V <sub>GS</sub> = 0 V, f = 1.0 MHz, V <sub>DS</sub> = 25 V         3000         According to the property of the	CHARGES, CAPACITANCES AND GATE RE	SISTANCES						
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = 25 \text{ V}$			5400		pF
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Output Capacitance	C <sub>oss</sub>				3000		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Reverse Transfer Capacitance	C <sub>rss</sub>				71		
	Total Gate Charge	Q <sub>G(TOT)</sub>				80.6		nC
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 32 \text{ V},$ $I_{D} = 50 \text{ A}$			15.2		1
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate-to-Source Charge					25.2		1
	Gate-to-Drain Charge	$Q_{GD}$				15.4		
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Plateau Voltage	V <sub>GP</sub>				4.8		V
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	SWITCHING CHARACTERISTICS (Note 5)						1	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-On Delay Time	t <sub>d(on)</sub>				15		ns
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Rise Time	t <sub>r</sub>	Vcs = 10 V. Vp	e = 32 V		78		1
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D = 50 \text{ A}, R_G = 2.5 \Omega$			43		1
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Fall Time	t <sub>f</sub>				14		1
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	DRAIN-SOURCE DIODE CHARACTERISTIC	S					ı	<u> </u>
Reverse Recovery Time $t_{RR}$ $V_{GS} = 0 \text{ V, dls/dt} = 100 \text{ A/}\mu\text{s,}$ $0 \text{ Is} = 50 \text{ A}$	Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = 0 V,$ $I_{S} = 50 A$	T <sub>J</sub> = 25°C		0.8	1.2	V
Charge Time ta $V_{GS} = 0 \text{ V, dIs/dt} = 100 \text{ A/}\mu\text{s,}$ $V_{GS} = 50 \text{ A}$ $V_{GS} = 50 \text{ A}$ $V_{GS} = 100 \text{ A/}\mu\text{s}$				T <sub>J</sub> = 125°C		0.7		1
Discharge Time $V_{GS} = 0 \text{ V, dis/dt} = 100 \text{ A/µs,}$ $I_S = 50 \text{ A}$ $37$	Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V}, \text{ dls/dt} = 100 \text{ A/}\mu\text{s},$			73		ns
Discharge Time tb I <sub>S</sub> = 50 A 37	Charge Time					36		
Reverse Recovery Charge Qpp 120 nC	Discharge Time	tb				37		
	Reverse Recovery Charge	Q <sub>RR</sub>				120		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

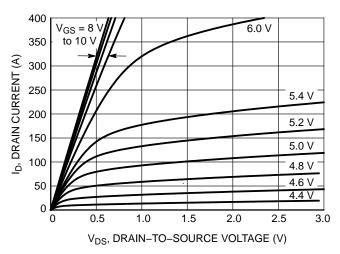


Figure 1. On-Region Characteristics

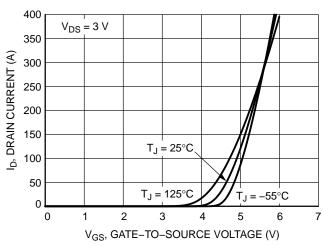


Figure 2. Transfer Characteristics

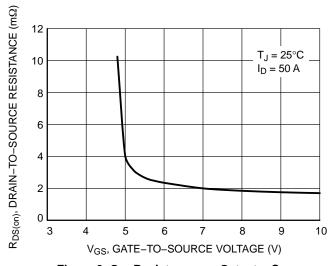


Figure 3. On–Resistance vs. Gate–to–Source Voltage

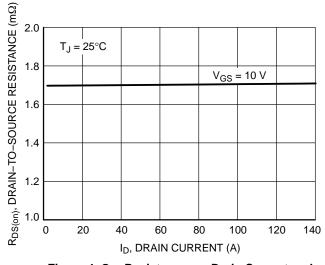


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

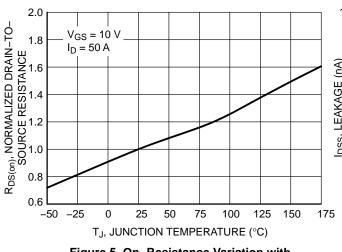


Figure 5. On–Resistance Variation with Temperature

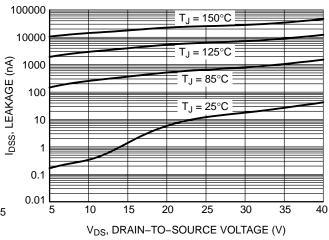


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

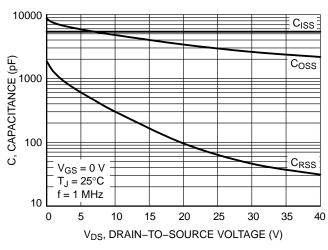


Figure 7. Capacitance Variation

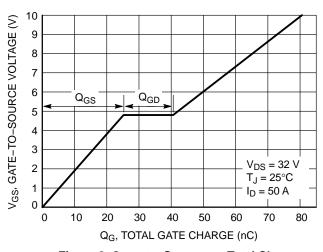


Figure 8. Gate-to-Source vs. Total Charge

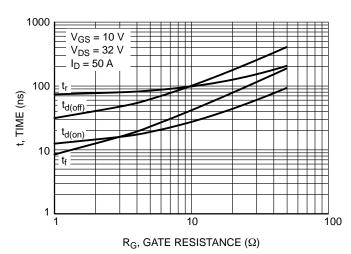


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

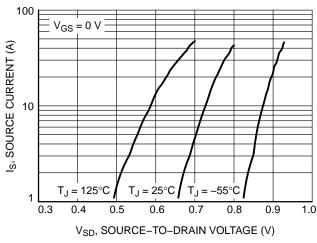


Figure 10. Diode Forward Voltage vs. Current

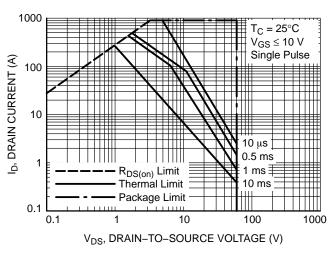


Figure 11. Maximum Rated Forward Biased Safe Operating Area

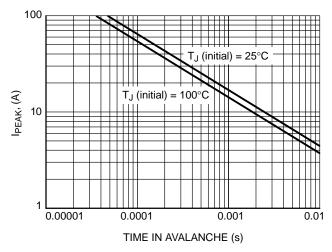


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

## **TYPICAL CHARACTERISTICS**

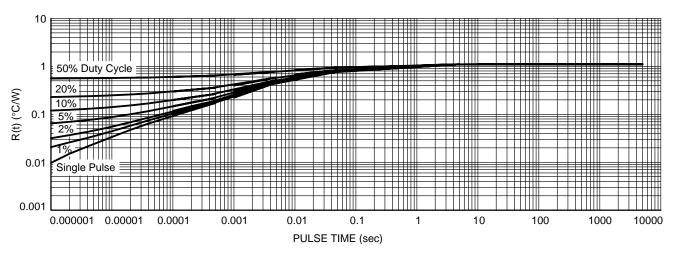


Figure 13. Thermal Characteristics

#### **ORDERING INFORMATION**

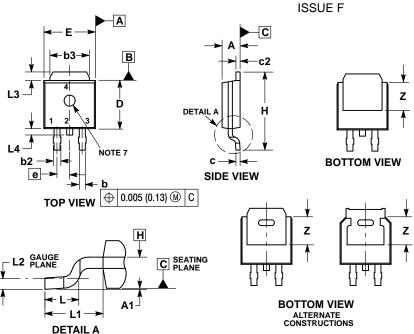
Order Number	Package	Shipping <sup>†</sup>
NVD5C434NT4G	DPAK (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

# **DPAK (SINGLE GAUGE)**

CASE 369C



- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 114.3WI, 1981
  2. CONTROLLING DIMENSION: INCHES.
  3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.
  4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY. 6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

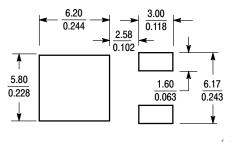
	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.028	0.045	0.72	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.114	0.114 REF		REF	
L2	0.020 BSC		0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2:

PIN 1. GATE 2. DRAIN

SOURCE DRAIN

#### **SOLDERING FOOTPRINT\***



(mm inches SCALE 3:1

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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